Automatic Test Committee
Chair’s Report

Les Orlidge
Slattery Award

• Winner: Michael Dewey
• Award will be presented at Awards Luncheon on Wednesday
  – You can register for lunch separately from Technical program
Upcoming NDIA SED Events

• 20th Annual Systems Engineering Conference
  Event #8870, October 23-26, 2017
  Waterford, Springfield, VA

• Annual Strategic Planning Session / SED Meeting
  December 6, 2017 in the Washington, DC area
  (TBD)
IEEE SCC20

- Ballot Closed - P1636  Draft Standard for Software Interface for Maintenance Information Collection and Analysis (SIMICA)
  - This standard is an implementation-independent specification for a software interface to information systems containing data pertinent to the diagnosis and maintenance of complex systems consisting of hardware, software, or any combination thereof.

- Ballot Closed – P1636.1  Draft Standard for SIMICA: Exchanging Test Results & Session Information via eXtensible Markup Language
  - Via XML and Web Ontology Language (OWL)

- Ballot Closed – P1636.2  Draft Standard for SIMICA: Exchanging Maintenance Action Information via eXtensible Markup Language
  - Information associated with the removal, repair, and replacement of system components to maintain/support an operation system
IEEE SCC20

• Recirculation Ballot Closed – P1671.1 Draft Standard for Automatic Test Markup Language (ATML) Test Description
  – Defines an exchange format, utilizing XML, for specifying test performance, test conditions, diagnostic requirements, and support equipment to locate, align, and verify the proper operation of a Unit Under Test (UUT).

• Recirculation Ballot Closed – P1671.3 Draft Standard for Automatic Test Markup Language (ATML) Unit Under Test (UUT) Description
  – Defines an exchange format, utilizing XML, for both the static description of unit under test (UUT), and the specific description of UUT instance information.
IEEE SCC20

• Recirculation Ballot to Open - P1871.2 Draft Recommended Practice for IEEE 1671 Test Equipment Templates and Extension Classes for Describing Intrinsic Signal Path Information for Cables, Interface Adapters and Test Equipment

Purpose:
– To document and enable programmatic access to the intrinsic characteristics of path related resources found in automated test systems via ATML
– To show best practices in how to extend ATML in order to gain access to more detailed intrinsic path characteristics that applications often require